

# SN54S8003, SN74S8003

## DUAL 2-INPUT POSITIVE-NAND GATES

SCAS429 – JANUARY 1991–REVISED OCTOBER 1992

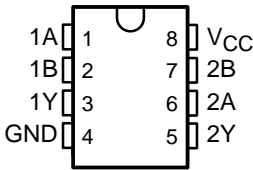
- Typical  $V_{OLP}$  (Output Ground Bounce) < 1 V at  $V_{CC} = 5$  V,  $T_A = 25^\circ\text{C}$
- Package Options Include Plastic Small-Outline Packages and Plastic DIPs

### description

The 'S8003 contains two independent 2-input NAND gates. It performs the Boolean functions  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic.

The SN54S8003 is characterized for operation over the full military temperature range of  $-55^\circ\text{C}$  to  $125^\circ\text{C}$ . The SN74S8003 is characterized for operation from  $0^\circ\text{C}$  to  $70^\circ\text{C}$ .

SN74S8003 . . . D OR P PACKAGE  
(TOP VIEW)



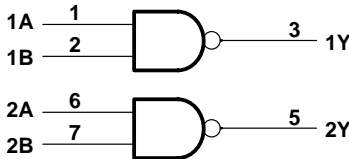
FUNCTION TABLE  
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

### logic symbol†



### logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, $V_{CC}$	7 V
Input voltage, $V_I$	5.5 V
Operating free-air temperature range: SN54S8003	$-55^\circ\text{C}$ to $125^\circ\text{C}$
SN74S8003	$0^\circ\text{C}$ to $70^\circ\text{C}$
Storage temperature range	$-65^\circ\text{C}$ to $150^\circ\text{C}$

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS  
INSTRUMENTS**

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## DUAL 2-INPUT POSITIVE-NAND GATES

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### recommended operating conditions

		SN54S8003			SN74S8003			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
$V_{CC}$	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.8			0.8	V
$I_{OH}$	High-level output current			–1			–1	mA
$I_{OL}$	Low-level output current			20			20	mA
$T_A$	Operating free-air temperature	–55		125	0		70	°C

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONST	SN54S8003			SN74S8003			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
$V_{IK}$	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			–1.2			–1.2	V
$V_{OH}$	$V_{CC} = \text{MIN}, V_{IL} = 0.8 \text{ V}, I_{OH} = -1 \text{ mA}$	2.5	3.4		2.7	3.4		V
$V_{OL}$	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 20 \text{ mA}$			0.5			0.5	V
$I_I$	$V_{CC} = \text{MAX}, V_I = 5.5 \text{ V}$			1			1	mA
$I_{IH}$	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$			50			50	µA
$I_{IL}$	$V_{CC} = \text{MAX}, V_I = 0.5 \text{ V}$			–2			–2	mA
$I_{OS}§$	$V_{CC} = \text{MAX}$	–40		–100	–40		–100	mA
$I_{CCH}$	$V_{CC} = \text{MAX}, V_I = 0$		6	10		6	10	mA
$I_{CCL}$	$V_{CC} = \text{MAX}, V_I = 4.5 \text{ V}$		14	20		14	20	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

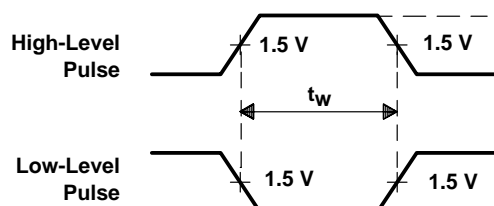
‡ All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

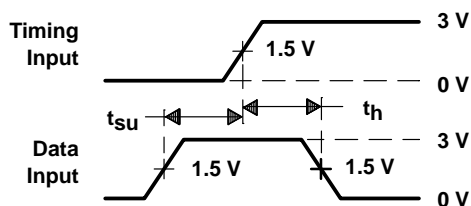
### switching characteristics, $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{PLH}$	A or B	Y	$R_L = 280 \Omega, C_L = 15 \text{ pF}$		3	4.5	ns
$t_{PHL}$					3	5	
$t_{PLH}$			$R_L = 280 \Omega, C_L = 50 \text{ pF}$		4.5		ns
$t_{PHL}$					5		

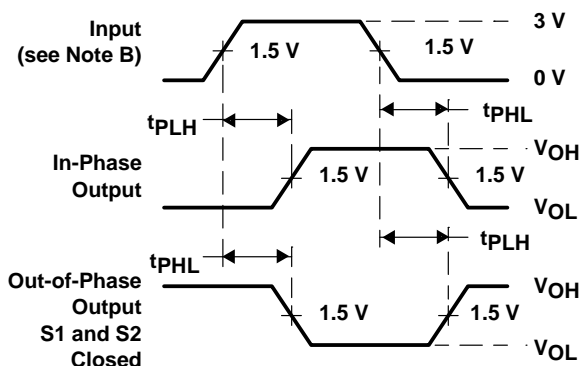
# PARAMETER MEASUREMENT INFORMATION



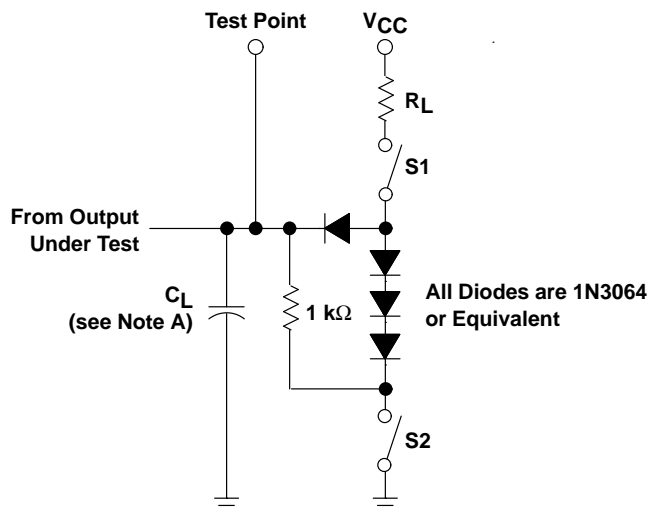
VOLTAGE WAVEFORMS  
PULSE DURATION



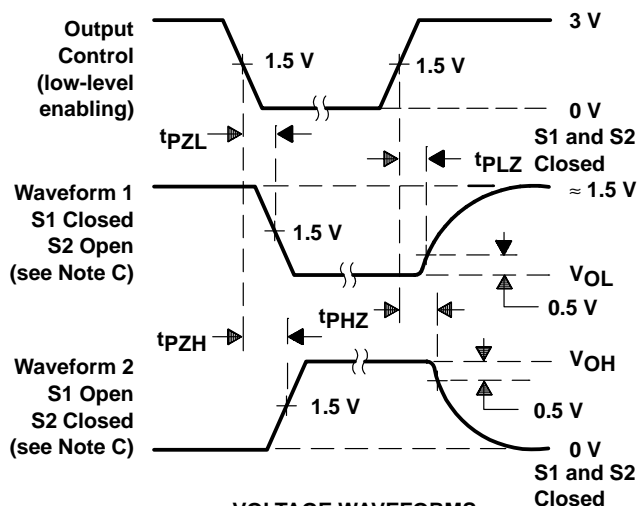
VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES



LOAD CIRCUIT FOR 3-STATE OUTPUTS



VOLTAGE WAVEFORMS  
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.  
B. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z<sub>0</sub> = 50 Ω, t<sub>r</sub> ≤ 2.5 ns, t<sub>f</sub> ≤ 2.5 ns.  
C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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